



## Product/Process Change Notice - PCN 22\_0199 Rev. -

Analog Devices, Inc. One Analog Way, Wilmington, MA 01887, USA

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

**PCN Title:** LTC2944 Die Revision  
**Publication Date:** 22-Aug-2022  
**Effectivity Date:** 24-Nov-2022 *(the earliest date that a customer could expect to receive changed material)*

**Revision Description:**  
Initial Release

**Description Of Change:**  
Minor SiCr resistor layout edit.

### Reason For Change:

The layout change is to minimize performance variations and to ensure stable yield in production.

### Impact of the change (positive or negative) on fit, form, function & reliability:

No impact to fit, form or reliability.

### Product Identification *(this section will describe how to identify the changed material)*

The parts that will be assembled with the new die will be identified by the datecode.

### Summary of Supporting Information:

Qualification has been performed per AEC-Q100, Stress Test Qualification for Integrated Circuits. See attached Qualification Results.

### Supporting Documents

**Attachment 1: Type:** Qualification Results Summary  
ADI\_PCN\_22\_0199\_Rev\_-\_LTC2944 PCN Report.pdf

**Attachment 2: Type:** Delta Qualification Matrix  
ADI\_PCN\_22\_0199\_Rev\_-\_LTC2944 VIS PCN 22\_0199-Delta-Qualification-Matrix-ZVEI-5\_0\_9.xlsm

**For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.**

**Americas:**  
PCN\_Americas@analog.com

**Europe:**  
PCN\_Europe@analog.com

**Japan:**  
PCN\_Japan@analog.com

**Rest of Asia:**  
PCN\_ROA@analog.com

**Appendix A - Affected ADI Models**

**Added Parts On This Revision - Product Family / Model Number (5)**

LTC2944 / LTC2944CDD#PBF

LTC2944 / LTC2944CDD#TRPBF

LTC2944 / LTC2944IDD#3ZZPBF

LTC2944 / LTC2944IDD#PBF

LTC2944 / LTC2944IDD#TRPBF

**Appendix B - Revision History**

<b>Rev</b>	<b>Publish Date</b>	<b>Effectivity Date</b>	<b>Rev Description</b>
Rev. -	22-Aug-2022	24-Nov-2022	Initial Release

Analog Devices, Inc.

DocId:8988 Parent DocId:8969 Layout Rev:8

## Qualification Results Summary LTC2944

LTC2944 Reliability Report Summary			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A101</i>	<b>3*77</b>	<b>Pass</b>
Temperature Cycle (TC)*	JEDEC <i>JESD22-A104</i>	<b>3*77</b>	<b>Pass</b>
Autoclave (AC)*	JEDEC <i>JESD22-A102</i>	<b>3*77</b>	<b>Pass</b>
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	<b>1*45</b>	<b>Pass</b>
High Temperature Operating Life (HTOL)	JEDEC <i>JESD22-A108</i>	<b>3*77</b>	<b>Pass</b>
Early Life Failure Rate (ELFR)	AEC-Q100-008	<b>3*800</b>	<b>Pass</b>
Latch-Up	JEDEC <i>JESD78</i>	<b>1*5</b>	<b>Pass</b>
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	<b>3/voltage</b>	<b>Pass</b>
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	<b>3/voltage</b>	<b>Pass</b>

\* Preconditioned per JEDEC/IPC J-STD-020